

40V N-Channel Enhancement Mode MOSFET

Description

The AP380N04SLG5 uses advanced **APM-SGT V** technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 10V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

 $V_{DS} = 40V I_{D} = 380A$

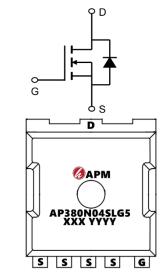
 $R_{DS(ON)} < 1.0 m\Omega$ @ V_{GS} =10V (Type: 0.75m Ω)

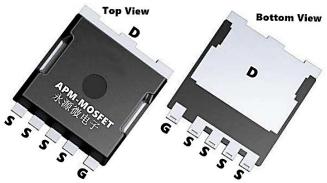
Application

BMS

BLDC

UPS





Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP380N04SLG5	STOLL-6L	AP380N04SLG5 XXX YYYY	2000

Absolute Maximum Ratings (T_C=25[°]Cunless otherwise noted)

Symbol	Parameter	Max.	Units
VDSS	Drain-Source Voltage	40	V
VGSS	Gate-Source Voltage	±20	V
ID@TC=25°C	Continuous Drain Current, VGS @ 10V1	380	А
ID@TC=100℃	Continuous Drain Current, VGS @ 10V1	280	А
IDM	Pulsed Drain Current	1250	А
EAS	Single Pulsed Avalanche Energy	627.2	mJ
IAS	Avalanche Current	70	А
PD@TC=25℃	Power Dissipation	65.7	W
T _J ,TSTG	Storage Temperature Range	-55 to 175	°C
R₀JA	Thermal Resistance Junction-Ambient ¹	40	°C/W
RθJC	Thermal Resistance, Junction to Case	1.9	°C/W



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Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units
V(BR)DSS	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	40	45	-	V
IDSS	Zero Gate Voltage Drain Current	V _{DS} =40V, V _{GS} =0V,	-	-	1.0	μΑ
IGSS	Gate to Body Leakage Current	V _{DS} =0V, V _{GS} = ±20V	-	-	±100	nA
VGS(th)	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	2.0	3.0	4.0	V
RDS(on)	Static Drain-Source on-Resistance	V _{GS} =10V, I _D =30A	-	0.75	1.0	mΩ
Ciss	Input Capacitance		-	6650	-	pF
Coss	Output Capacitance	V _{DS} =20V, V _{GS} =0V, f=1.0MHz	-	1495	-	pF
Crss	Reverse Transfer Capacitance		-	103	-	pF
Qg	Total Gate Charge	V _{DS} =20V, I _D =20A, V _{GS} =10V	-	118	-	nC
Qgs	Gate-Source Charge		-	19	-	nC
Qgd	Gate-Drain("Miller") Charge	100 101	_	22.2	-	nC
td(on)	Turn-on Delay Time		-	13.8	-	ns
tr	Turn-on Rise Time	V _{DD} =20V, I _D =20A,	_	14	-	ns
td(off)	Turn-off Delay Time	R _G =3Ω, V _{GS} =10V	_	91	-	ns
t _f	Turn-off Fall Time		-	43	-	ns
IS	Maximum Continuous Drain to Source Diode Forward Current		-	-	200	Α
ISM	Maximum Pulsed Drain to Source Diode Forward Current		-	-	800	Α
VSD	Drain to Source Diode Forward Voltage	V _{GS} =0V, I _S =20A	-	-	1.2	V
trr	Body Diode Reverse Recovery Time	T _J =25°C,IF=20A	-	66	-	ns
Qrr	Body Diode Reverse Recovery Charge	I _F =I _S ,dI/dt=100A/μs	-	39.6	-	nC

Note:

- 1. The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
- 2_{\times} The data tested by pulsed , pulse width \leqq 300us , duty cycle \leqq 2%
- 3 The EAS data shows Max. rating . The test condition is VDD=32V,VGS =10V,L=0.1mH,IAS =70A
- 4. The power dissipation is limited by 150 ℃ junction temperature
- 5. The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.



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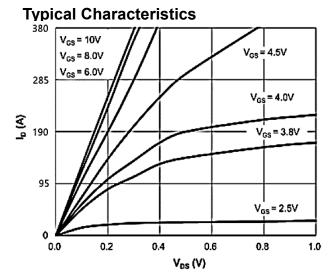


Figure 1. Output Characteristics

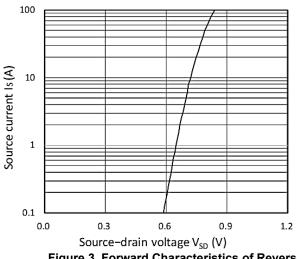


Figure 3. Forward Characteristics of Reverse

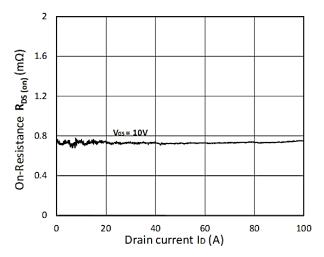


Figure 5. RDS(ON) vs. ID

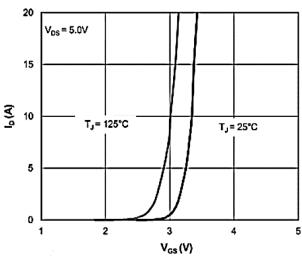


Figure 2. Transfer Characteristics

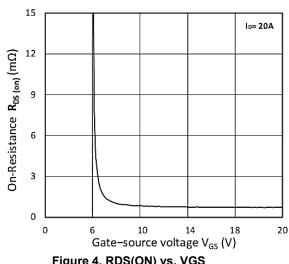


Figure 4. RDS(ON) vs. VGS

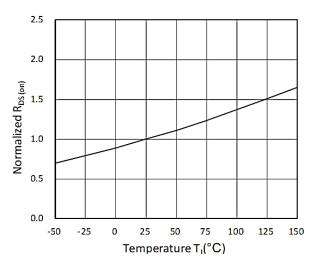


Figure 6. Normalized RDS(on) vs. Temperature





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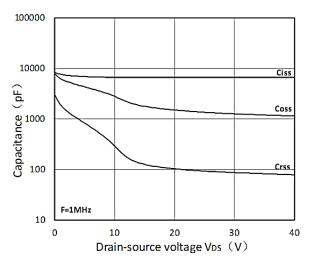


Figure 7. Capacitance Characteristics

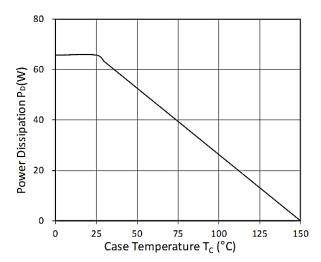


Figure 9. Power Dissipation

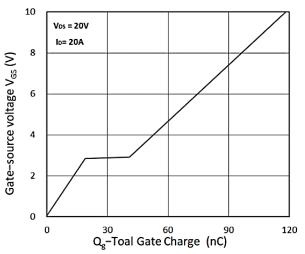


Figure 8. Gate Charge Characteristics

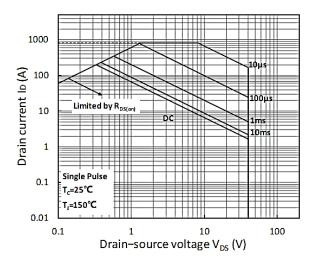


Figure 10. Safe Operating Area

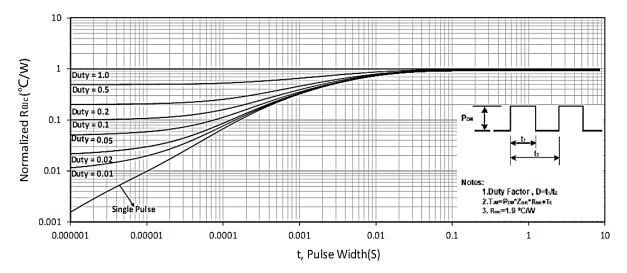
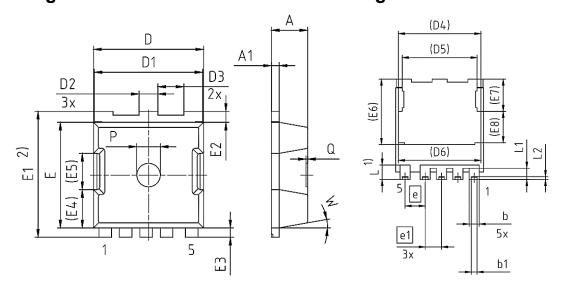


Figure 11 Normalized Maximum Transient Thermal Impedance



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Package Mechanical Data-STOLL-6L-JJ Single



Symbol	Dimensions In Millimeters		
Symbol	Min.	Max.	
A	2.2	2.4	
A1	0.40	0.60	
b	0.70	0.90	
b1	0.42	0.50	
D	6.80	7.20	
D1	6.80	7.00	
D2	1.10	1.30	
D3	1.55	1.75	
D4	6.56		
D5	5.96		
D6	5.60		
E	6.50	6.90	
E1	7.80	8.20	
E2	0.60	0.80	
E3	0.50	0.70	
E4	2.43		
E5	2.30		
E6	5.20		
E7	2.57		
E8	2.50		
е	1.60		
e1	1.30		
L	1.05	1.25	
L1	0.80	1.00	
L2	0.13	0.33	
P	1.40	1.60	
Q	0.00	0.10	
W	8.50°	11.50°	



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Edition	Date	Change
REV1.0	2023/5/31	Initial release

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